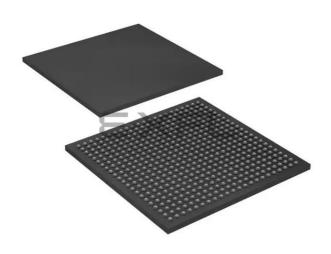
Intel - EP4CGX75CF23I7N Datasheet





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Details

Detuns	
Product Status	Active
Number of LABs/CLBs	4620
Number of Logic Elements/Cells	73920
Total RAM Bits	4257792
Number of I/O	290
Number of Gates	-
Voltage - Supply	1.16V ~ 1.24V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4cgx75cf23i7n

Email: info@E-XFL.COM

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Table 1-3.	Recommended Operating Conditions for Cyclone IV E Devices ^{(1), (2}	⁹ (Part 2 of 2)
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Symbol	Parameter	Parameter Conditions		Тур	Max	Unit
I _{Diode}	Magnitude of DC current across PCI-clamp diode when enable	_	_		10	mA

Notes to Table 1–3:

 Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades.

(2) V_{CCI0} for all I/O banks must be powered up during device operation. All vCCA pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.

(3) V_{CC} must rise monotonically.

(4) V_{CCI0} powers all input buffers.

(5) The POR time for Standard POR ranges between 50 and 200 ms. Each individual power supply must reach the recommended operating range within 50 ms.

(6) The POR time for Fast POR ranges between 3 and 9 ms. Each individual power supply must reach the recommended operating range within 3 ms.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{ccint} <i>(3)</i>	Core voltage, PCIe hard IP block, and transceiver PCS power supply	• • • • • • • • • • • • • • • • • • •				
V _{CCA} (1), (3)	PLL analog power supply	_	2.375	2.5	2.625	V
V _{CCD_PLL} <i>(2)</i>	PLL digital power supply	_	1.16	1.2	1.24	V
	I/O banks power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	I/O banks power supply for 3.0-V operation	—	2.85	3	3.15	V
V _{ccio} <i>(3), (4)</i>	I/O banks power supply for 2.5-V operation	_	2.375	2.5	2.625	V
operation	I/O banks power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	I/O banks power supply for 1.5-V operation	—	1.425	1.5	1.575	V
I/O banks power supply for 1.2-V operation		_	1.14	1.2	1.26	V
	Differential clock input pins power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	Differential clock input pins power supply for 3.0-V operation	—	2.85	3	3.15	V
V _{CC_CLKIN} (3), (5), (6)	Differential clock input pins power supply for 2.5-V operation	—	2.375	2.5	2.625	V
	Differential clock input pins power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	Differential clock input pins power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	Differential clock input pins power supply for 1.2-V operation	—	1.14	1.2	1.26	V
V _{CCH_GXB}	Transceiver output buffer power supply	_	2.375	2.5	2.625	V

Table 1–4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CCA_GXB}	Transceiver PMA and auxiliary power supply	_	2.375	2.5	2.625	V
V _{CCL_GXB}	Transceiver PMA and auxiliary power supply	_	1.16	1.2	1.24	V
VI	DC input voltage	—	-0.5		3.6	V
V ₀	DC output voltage	—	0	—	V _{CCIO}	V
т	Operating junction temperature	For commercial use	0	—	85	°C
TJ	Operating junction temperature	For industrial use	-40		100	°C
t _{RAMP}	Power supply ramp time	Standard power-on reset (POR) ⁽⁷⁾	50 µs	_	50 ms	_
		Fast POR ⁽⁸⁾	50 µs		3 ms	_
I _{Diode}	Magnitude of DC current across PCI-clamp diode when enabled	_	_	_	10	mA

Table 1-4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 2 of 2)

Notes to Table 1-4:

- (1) All VCCA pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.
- (2) You must connect $V_{CCD PLL}$ to V_{CCINT} through a decoupling capacitor and ferrite bead.
- (3) Power supplies must rise monotonically.
- (4) V_{CCI0} for all I/O banks must be powered up during device operation. Configurations pins are powered up by V_{CCI0} of I/O Banks 3, 8, and 9 where I/O Banks 3 and 9 only support V_{CCI0} of 1.5, 1.8, 2.5, 3.0, and 3.3 V. For fast passive parallel (FPP) configuration mode, the V_{CCI0} level of I/O Bank 8 must be powered up to 1.5, 1.8, 2.5, 3.0, and 3.3 V.
- (5) You must set $V_{CC_{CLKIN}}$ to 2.5 V if you use CLKIN as a high-speed serial interface (HSSI) refclk or as a DIFFCLK input.
- (6) The CLKIN pins in I/O Banks 3B and 8B can support single-ended I/O standard when the pins are used to clock left PLLs in non-transceiver applications.
- (7) The POR time for Standard POR ranges between 50 and 200 ms. V_{CCINT}, V_{CCA}, and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 50 ms.
- (8) The POR time for Fast POR ranges between 3 and 9 ms. V_{CCINT}, V_{CCA}, and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 3 ms.

ESD Performance

This section lists the electrostatic discharge (ESD) voltages using the human body model (HBM) and charged device model (CDM) for Cyclone IV devices general purpose I/Os (GPIOs) and high-speed serial interface (HSSI) I/Os. Table 1–5 lists the ESD for Cyclone IV devices GPIOs and HSSI I/Os.

Table 1–5. ESD for Cyclone IV Devices GPIOs and HSSI I/0
--

Symbol	Parameter	Passing Voltage	Unit
M	ESD voltage using the HBM (GPIOs) ⁽¹⁾	± 2000	V
VESDHBM	ESD using the HBM (HSSI I/Os) ⁽²⁾	± 1000	V
V	ESD using the CDM (GPIOs)	± 500	V
VESDCDM	ESD using the CDM (HSSI I/Os) ⁽²⁾	± 250	V

Notes to Table 1-5:

(1) The passing voltage for EP4CGX15 and EP4CGX30 row I/Os is ±1000V.

(2) This value is applicable only to Cyclone IV GX devices.

DC Characteristics

This section lists the I/O leakage current, pin capacitance, on-chip termination (OCT) tolerance, and bus hold specifications for Cyclone IV devices.

Supply Current

The device supply current requirement is the minimum current drawn from the power supply pins that can be used as a reference for power size planning. Use the Excel-based early power estimator (EPE) to get the supply current estimates for your design because these currents vary greatly with the resources used. Table 1–6 lists the I/O pin leakage current for Cyclone IV devices.

Table 1–6. I/O Pin Leakage Current for Cyclone IV Devices (1), (2)

Symbol	Parameter	Conditions	Device	Min	Тур	Max	Unit
I _I	Input pin leakage current	$V_I = 0 V \text{ to } V_{CCIOMAX}$	_	-10	_	10	μA
I _{OZ}	Tristated I/O pin leakage current	$V_0 = 0 V$ to $V_{CCIOMAX}$		-10		10	μΑ

Notes to Table 1-6:

(1) This value is specified for normal device operation. The value varies during device power-up. This applies for all V_{CCI0} settings (3.3, 3.0, 2.5, 1.8, 1.5, and 1.2 V).

(2) The 10 μ A I/O leakage current limit is applicable when the internal clamping diode is off. A higher current can be observed when the diode is on.

Bus Hold

The bus hold retains the last valid logic state after the source driving it either enters the high impedance state or is removed. Each I/O pin has an option to enable bus hold in user mode. Bus hold is always disabled in configuration mode.

Table 1–7 lists bus hold specifications for Cyclone IV devices.

 Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 1 of 2)⁽¹⁾

		V _{CCI0} (V)												
Parameter	Condition	1	.2	1	.5	1	.8	2	.5	3	.0	3	.3	Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold low, sustaining current	V _{IN} > V _{IL} (maximum)	8	_	12	_	30	_	50	_	70	_	70	_	μА
Bus hold high, sustaining current	V _{IN} < V _{IL} (minimum)	-8	_	-12	_	-30		-50	_	-70	_	-70	_	μΑ
Bus hold low, overdrive current	$0 V < V_{\rm IN} < V_{\rm CCI0}$	_	125		175	_	200	_	300		500		500	μA
Bus hold high, overdrive current	$0 \text{ V} < \text{V}_{\text{IN}} < \text{V}_{\text{CCIO}}$	_	-125	_	-175		-200		-300		-500		-500	μА

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up. Use Table 1–10 and Equation 1–1 to determine the final OCT resistance considering the variations after calibration at device power-up. Table 1–10 lists the change percentage of the OCT resistance with voltage and temperature.

Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	-0.026
2.5	0.234	-0.039
1.8	0.219	-0.086
1.5	0.199	-0.136
1.2	0.161	-0.288

Equation 1–1. Final OCT Resistance ^{(1), (2), (3), (4), (5), (6)}

$$\begin{split} &\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV - (7) \\ &\Delta R_T = (T_2 - T_1) \times dR/dT - (8) \\ &For \ \Delta R_x < 0; \ MF_x = 1/ \ (|\Delta R_x|/100 + 1) - (9) \\ &For \ \Delta R_x > 0; \ MF_x = \Delta R_x/100 + 1 - (10) \\ &MF = MF_V \times MF_T - (11) \\ &R_{final} = R_{initial} \times MF - (12) \end{split}$$

Notes to Equation 1–1:

- (1) T_2 is the final temperature.
- (2) T_1 is the initial temperature.
- (3) MF is multiplication factor.
- (4) R_{final} is final resistance.
- (5) R_{initial} is initial resistance.
- (6) Subscript $_x$ refers to both $_V$ and $_T$.
- (7) ΔR_V is a variation of resistance with voltage.
- (8) ΔR_T is a variation of resistance with temperature.
- (9) dR/dT is the change percentage of resistance with temperature after calibration at device power-up.
- (10) dR/dV is the change percentage of resistance with voltage after calibration at device power-up.

(11) V_2 is final voltage.

(12) V_1 is the initial voltage.

Example 1–1 shows how to calculate the change of 50- Ω I/O impedance from 25°C at 3.0 V to 85°C at 3.15 V.

Example 1–1. Impedance Change

$$\begin{split} \Delta R_V &= (3.15-3) \times 1000 \times -0.026 = -3.83 \\ \Delta R_T &= (85-25) \times 0.262 = 15.72 \\ \text{Because } \Delta R_V \text{ is negative,} \\ MF_V &= 1 \ / \ (3.83/100 + 1) = 0.963 \\ \text{Because } \Delta R_T \text{ is positive,} \\ MF_T &= 15.72/100 + 1 = 1.157 \\ MF &= 0.963 \times 1.157 = 1.114 \\ R_{\text{final}} &= 50 \times 1.114 = 55.71 \ \Omega \end{split}$$

Pin Capacitance

Table 1–11 lists the pin capacitance for Cyclone IV devices.

Symbol	Parameter	Typical – Quad Flat Pack (QFP)	Typical – Quad Flat No Leads (QFN)	Typical – Ball-Grid Array (BGA)	Unit
C _{IOTB}	Input capacitance on top and bottom I/O pins	7	7	6	pF
C _{IOLR}	Input capacitance on right I/O pins	7	7	5	pF
C_{LVDSLR}	Input capacitance on right I/O pins with dedicated LVDS output	8	8	7	pF
C _{VREFLR}	Input capacitance on right dual-purpose ${\tt VREF}$ pin when used as $V_{\sf REF}$ or user I/O pin	21	21	21	pF
C _{VREFTB}	Input capacitance on top and bottom dual-purpose ${\tt VREF}$ pin when used as $V_{\sf REF}$ or user I/O pin	23 <i>(3)</i>	23	23	pF
C _{CLKTB}	Input capacitance on top and bottom dedicated clock input pins	7	7	6	pF
C _{CLKLR}	Input capacitance on right dedicated clock input pins	6	6	5	pF

Notes to Table 1-11:

(1) The pin capacitance applies to FBGA, UBGA, and MBGA packages.

(2) When you use the vref pin as a regular input or output, you can expect a reduced performance of toggle rate and t_{CO} because of higher pin capacitance.

(3) C_{VREFTB} for the EP4CE22 device is 30 pF.

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1–12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1–12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_{CCIO} = 3.3 \text{ V} \pm 5\%$ (2), (3)	7	25	41	kΩ
	Value of the I/O pin pull-up resistor	$V_{CCIO} = 3.0 \text{ V} \pm 5\%$ (2), (3)	7	28	47	kΩ
R	before and during configuration, as	$V_{CCIO} = 2.5 \text{ V} \pm 5\%$ (2), (3)	8	35	61	kΩ
R_pu	well as user mode if you enable the	$V_{CCIO} = 1.8 \text{ V} \pm 5\%$ (2), (3)	10	57	108	kΩ
	programmable pull-up resistor option	$V_{CCIO} = 1.5 \text{ V} \pm 5\%$ (2), (3)	13	82	163	kΩ
		$V_{CCIO} = 1.2 \text{ V} \pm 5\%$ (2), (3)	19	143	351	kΩ
		$V_{CCIO} = 3.3 \text{ V} \pm 5\%$ (4)	6	19	30	kΩ
		$V_{CCIO} = 3.0 \text{ V} \pm 5\%$ (4)	6	22	36	kΩ
R_pd	Value of the I/O pin pull-down resistor before and during configuration	$V_{CCIO} = 2.5 \text{ V} \pm 5\%$ (4)	6	25	43	kΩ
		$V_{CCIO} = 1.8 \text{ V} \pm 5\%$ (4)	7	35	71	kΩ
		$V_{CCIO} = 1.5 V \pm 5\%$ (4)	8	50	112	kΩ

Notes to Table 1–12:

- (1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.
- (2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO} .
- $\begin{array}{ll} \text{(3)} & \text{R}_{_{PU}} = (\text{V}_{\text{CCI0}} \text{V}_{\text{I}})/\text{I}_{\text{R}_{_{PU}}} \\ & \text{Minimum condition: } -40^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}} + 5\%, \ \text{V}_{\text{I}} = \text{V}_{\text{CC}} + 5\% 50 \ \text{mV}; \\ & \text{Typical condition: } 25^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}}, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = 10^{\circ}\text{C}; \ \text{V}_{\text{CO}} = 10^{\circ$
- $\begin{array}{ll} (4) & R_{_PD} = V_I/I_{R_PD} \\ & \text{Minimum condition:} -40^{\circ}\text{C}; \ V_{CCIO} = V_{CC} + 5\%, \ V_I = 50 \ \text{mV}; \\ & \text{Typical condition:} \ 25^{\circ}\text{C}; \ V_{CCIO} = V_{CC}, \ V_I = V_{CC} 5\%; \\ & \text{Maximum condition:} \ 100^{\circ}\text{C}; \ V_{CCIO} = V_{CC} 5\%, \ V_I = V_{CC} 5\%; \ \text{in which } V_I \ \text{refers to the input voltage at the I/O pin.} \end{array}$

Hot-Socketing

Table 1–13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1–13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Parameter	Maximum
I _{IOPIN(DC)}	DC current per I/O pin	300 μA
I _{IOPIN(AC)}	AC current per I/O pin	8 mA <i>(1)</i>
I _{XCVRTX(DC)}	DC current per transceiver TX pin	100 mA
I _{XCVRRX(DC)}	DC current per transceiver RX pin	50 mA

Note to Table 1-13:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, |IIOPIN| = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.

During hot-socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF.

I/O		V _{ccio} (V))		V _{REF} (V)			V _{TT} (V) ⁽²⁾	
Standard	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 x V _{CCI0} (3) 0.47 x V _{CCI0} (4)	$\begin{array}{c} 0.5 \mbox{ x } V_{\rm CC10} \ \ {}^{(3)} \\ 0.5 \mbox{ x } V_{\rm CC10} \ \ {}^{(4)} \end{array}$	$\begin{array}{l} 0.52 \times V_{\rm CCI0} \ {}^{(3)} \\ 0.53 \times V_{\rm CCI0} \ {}^{(4)} \end{array}$	_	0.5 x V _{CCIO}	_

Notes to Table 1–16:

(1) For an explanation of terms used in Table 1–16, refer to "Glossary" on page 1–37.

(2) $\,\,V_{TT}$ of the transmitting device must track V_{REF} of the receiving device.

(3) Value shown refers to DC input reference voltage, $V_{\text{REF(DC)}}.$

(4) Value shown refers to AC input reference voltage, $V_{\text{REF(AC)}}$.

Table 1-17.	Single-Ended SSTL and HST	L I/O Standards Signal S	Specifications for C	yclone IV Devices
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I/O	V _{IL(}	_(DC) (V)	VIII	_{I(DC)} (V)	V _{IL(}	_{AC)} (V)	VIH	_(AC) (V)	V _{OL} (V)	V _{oh} (V)	I _{OL}	I _{oh}
Standard	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min	(mĀ)	(mÄ)
SSTL-2 Class I		V _{REF} – 0.18	V _{REF} + 0.18	_		V _{REF} – 0.35	V _{REF} + 0.35	—	V _{ττ} – 0.57	V _{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	_	V _{REF} – 0.18	V _{REF} + 0.18	—	_	V _{REF} – 0.35	V _{REF} + 0.35	—	V _{TT} – 0.76	V _{TT} + 0.76	16.4	-16.4
SSTL-18 Class I	_	V _{REF} – 0.125	V _{REF} + 0.125	—	_	V _{REF} – 0.25	V _{REF} + 0.25	—	V _{TT} – 0.475	V _{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	_	V _{REF} – 0.125	V _{REF} + 0.125	_	_	V _{REF} – 0.25	V _{REF} + 0.25	—	0.28	V _{CCI0} – 0.28	13.4	-13.4
HSTL-18 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	—	_	V _{REF} – 0.2	V _{REF} + 0.2	—	0.4	V _{CCI0} – 0.4	8	-8
HSTL-18 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	—	_	V _{REF} – 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} – 0.4	16	-16
HSTL-15 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	—	_	V _{REF} – 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} – 0.4	8	-8
HSTL-15 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	_	_	V _{REF} – 0.2	V _{REF} + 0.2	_	0.4	V _{CCI0} – 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCI0} + 0.15	-0.24	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCI0} + 0.24	0.25 × V _{CCI0}	0.75 × V _{CCI0}	8	-8
HSTL-12 Class II	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCI0} + 0.15	-0.24	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCI0} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14

• For more information about receiver input and transmitter output waveforms, and for other differential I/O standards, refer to the *I/O Features in Cyclone IV Devices* chapter.

Table 1–18. Differential SSTL I/O Standard Specifications for Cyclone IV Devices (1)

I/O Standard	V _{CCIO} (V)			V_{Swing}	_{I(DC)} (V)	V _{X(AC)} (V)			V _{Swi}	ng(AC) /)	V _{OX(AC)} (V)		
	Min Typ Max Min Max		Max	Min	Тур	Max	Min	Max	Min	Тур	Max		
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V _{CCIO}	$V_{CCIO}/2 - 0.2$	_	V _{CCI0} /2 + 0.2	0.7	V _{CCI} 0	V _{CCIO} /2 – 0.125		V _{CCI0} /2 + 0.125
SSTL-18 Class I, II	1.7	1.8	1.90	0.25	V _{CCIO}	V _{CCIO} /2 – 0.175	_	V _{CCI0} /2 + 0.175	0.5	V _{CCI} 0	V _{CCIO} /2 – 0.125	_	V _{CCI0} /2 + 0.125

Note to Table 1–18:

(1) Differential SSTL requires a V_{REF} input.

Table 1–19. Differential HSTL I/O Standard Specifications for Cyclone IV Devices ⁽¹⁾

	V	V _{CCIO} (V)	V _{DIF(}	_{DC)} (V)	Vx	(V) (X)		V _{CM(DC)} (V)				_{F(AC)} (V)
I/O Standard	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Тур	Max	Mi n	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	_	0.85	—	0.95	0.85	—	0.95	0.4	_
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	_	0.71	_	0.79	0.71	_	0.79	0.4	_
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V _{CCIO}	$0.48 \times V_{CCIO}$	_	0.52 x V _{CCI0}	0.48 x V _{CCIO}	_	0.52 x V _{CCI0}	0.3	0.48 x V _{CCI0}

Note to Table 1-19:

(1) Differential HSTL requires a V_{REF} input.

 Table 1–20. Differential I/O Standard Specifications for Cyclone IV Devices ⁽¹⁾ (Part 1 of 2)

I/O Standard	V _{CCIO} (V)			V _{ID} (mV)		V _{ICM} (V) ⁽²⁾			V _{0D} (mV) ⁽³⁾			V _{0S} (V) ⁽³⁾		
i/U Stalluaru	Min	Тур	Max	Min	Max	Min	Condition	Max	Min	Тур	Max	Min	Тур	Max
						0.05	$D_{MAX} \leq 500 \; Mbps$	1.80						
LVPECL (Row I/Os) (6)	2.375	2.5	2.625	100	_	0.55	$\begin{array}{l} 500 \text{ Mbps} \leq \text{ D}_{\text{MAX}} \\ \leq 700 \text{ Mbps} \end{array}$	1.80	_	—	_	—	—	_
						1.05	D _{MAX} > 700 Mbps	1.55						
						0.05	$D_{MAX} \leq ~500~Mbps$	1.80						
LVPECL (Column I/Os) <i>(6)</i>	2.375	2.5	2.625	100		0.55	$\begin{array}{l} 500 \text{ Mbps} \leq \text{D}_{\text{MAX}} \\ \leq 700 \text{ Mbps} \end{array}$	1.80	_	—	_	_	_	_
1/03/						1.05	D _{MAX} > 700 Mbps	1.55						
						0.05	$D_{MAX} \leq 500 \; Mbps$	1.80						
VDS (Row /Os)	2.375	.375 2.5	2.625	100	—	0.55	$\begin{array}{l} 500 \text{ Mbps} \leq \text{D}{\text{MAX}} \\ \leq \ 700 \text{ Mbps} \end{array}$	1.80	247	—	600	1.125	1.25	1.375
						1.05	D _{MAX} > 700 Mbps	1.55						

Power Consumption

Use the following methods to estimate power for a design:

- the Excel-based EPE
- the Quartus[®] II PowerPlay power analyzer feature

The interactive Excel-based EPE is used prior to designing the device to get a magnitude estimate of the device power. The Quartus II PowerPlay power analyzer provides better quality estimates based on the specifics of the design after place-and-route is complete. The PowerPlay power analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, combined with detailed circuit models, can yield very accurate power estimates.

To For more information about power estimation tools, refer to the *Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in volume 3 of the *Quartus II Handbook*.

Switching Characteristics

This section provides performance characteristics of Cyclone IV core and periphery blocks for commercial grade devices.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The upper-right hand corner of these tables show the designation as "Preliminary".
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Symbol/	Oggelitions		C6			C7, I7			C 8		
Description	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Receiver					•	•		•	•		
Supported I/O Standards	1.4 V PCML, 1.5 V PCML, 2.5 V PCML, LVPECL, LVDS										
Data rate (F324 and smaller package) ⁽¹⁵⁾	_	600	_	2500	600	_	2500	600	_	2500	Mbps
Data rate (F484 and larger package) ⁽¹⁵⁾	—	600	_	3125	600	_	3125	600	_	2500	Mbps
Absolute V _{MAX} for a receiver pin <i>(3)</i>	—	_	_	1.6	_	_	1.6	_	_	1.6	V
Operational V _{MAX} for a receiver pin	—	_	_	1.5	_	_	1.5	_	_	1.5	V
Absolute V _{MIN} for a receiver pin	_	-0.4	_	_	-0.4	_	_	-0.4	_	_	V
Peak-to-peak differential input voltage V _{ID} (diff p-p)	V _{ICM} = 0.82 V setting, Data Rate = 600 Mbps to 3.125 Gbps	0.1	_	2.7	0.1	_	2.7	0.1	_	2.7	V
V _{ICM}	V _{ICM} = 0.82 V setting	_	820 ± 10%	_	_	820 ± 10%	_	_	820 ± 10%	_	mV
Differential on-chip	100– Ω setting		100	—	_	100		_	100	—	Ω
termination resistors	150– Ω setting	—	150	_	_	150		_	150	—	Ω
Differential and common mode return loss	PIPE, Serial Rapid I/O SR, SATA, CPRI LV, SDI, XAUI					Compliant	Ľ				_
Programmable ppm detector ⁽⁴⁾	—				± 62.5	, 100, 128 250, 300					ppm
Clock data recovery (CDR) ppm tolerance (without spread-spectrum clocking enabled)				±300 <i>(5)</i> , ±350 <i>(6)</i> , <i>(7)</i>			±300 (5), ±350 (6), (7)		_	±300 (5), ±350 (6), (7)	ppm
CDR ppm tolerance (with synchronous spread-spectrum clocking enabled) ⁽⁸⁾	_	_	_	350 to 5350 (7), (9)	_		350 to 5350 (7), (9)	_		350 to 5350 (7), (9)	ppm
Run length	—		80		—	80	_	—	80		UI
	No Equalization		_	1.5	—	_	1.5	—	_	1.5	dB
Programmable	Medium Low		_	4.5	_	_	4.5	_		4.5	dB
equalization	Medium High		_	5.5	—		5.5	—	_	5.5	dB
	High	—		7	-	_	7	-	_	7	dB

Table 1–21.	Transceiver S	necification fo	r Cyclone	IV GX Devices	(Part 2 of 4)
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Figure 1–2 shows the lock time parameters in manual mode.

LTD = lock-to-data. LTR = lock-to-reference.

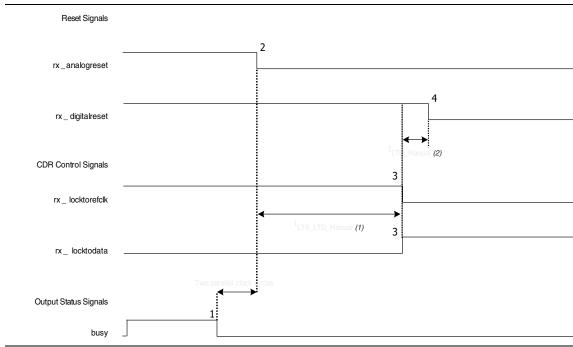


Figure 1–2. Lock Time Parameters for Manual Mode

Figure 1–3 shows the lock time parameters in automatic mode.

Figure 1–3. Lock Time Parameters for Automatic Mode

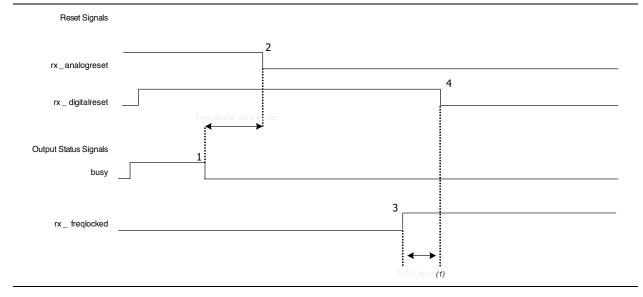


Table 1–23 lists the Cyclone IV GX transceiver block AC specifications.

Symbol/	0		C6			C7, 17	7		C 8		
Description	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
PCIe Transmit Jitter Gene	ration ⁽³⁾	-		<u>.</u>	-		<u>.</u>			<u>.</u>	
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	_	_	0.25	_	_	0.25	_	_	0.25	UI
PCIe Receiver Jitter Toler	ance ⁽³⁾	•						•	•		•
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern		> 0.6	6		> 0.6	;		> 0.6	;	UI
GIGE Transmit Jitter Gene	ration ⁽⁴⁾	•						•			•
Deterministic jitter	Pattern = CRPAT			0.14			0.14			0.14	UI
(peak-to-peak)	Falleni = UNFAI			0.14		_	0.14	_	_	0.14	01
Total jitter (peak-to-peak)	Pattern = CRPAT	—		0.279	_		0.279	_		0.279	UI
GIGE Receiver Jitter Toler	ance ⁽⁴⁾										
Deterministic jitter tolerance (peak-to-peak)	Pattern = CJPAT		> 0.4	ļ		> 0.4			> 0.4		UI
Combined deterministic and random jitter tolerance (peak-to-peak)	Pattern = CJPAT	> 0.66				> 0.66	6		6	UI	

Table 1–23. Transceiver Block AC Specification for Cyclone IV GX Devices (1), (2)

Notes to Table 1-23:

(1) Dedicated refclk pins were used to drive the input reference clocks.

(2) The jitter numbers specified are valid for the stated conditions only.

(3) The jitter numbers for PIPE are compliant to the PCIe Base Specification 2.0.

(4) The jitter numbers for GIGE are compliant to the IEEE802.3-2002 Specification.

Core Performance Specifications

The following sections describe the clock tree specifications, PLLs, embedded multiplier, memory block, and configuration specifications for Cyclone IV Devices.

Clock Tree Specifications

Table 1–24 lists the clock tree specifications for Cyclone IV devices.

 Table 1–24. Clock Tree Performance for Cyclone IV Devices (Part 1 of 2)

Device				Perfor	mance				11-14
Device	C6	C7	C8	C8L ⁽¹⁾	C9L ⁽¹⁾	17	18L ⁽¹⁾	A7	Unit
EP4CE6	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE10	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE15	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE22	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE30	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE40	500	437.5	402	362	265	437.5	362	402	MHz

Symbol	Parameter	Min	Тур	Max	Unit
t _{dlock}	Time required to lock dynamically (after switchover, reconfiguring any non-post-scale counters/delays or areset is deasserted)	_	_	1	ms
t _{outjitter_period_dedclk} (6)	Dedicated clock output period jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	300	ps
	F _{OUT} < 100 MHz	_	—	30	mUI
t _{outjitter_ccj_dedclk} (6)	Dedicated clock output cycle-to-cycle jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	300	ps
	F _{OUT} < 100 MHz	_	_	30	mUI
t _{outjitter_period_10} (6)	Regular I/O period jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	650	ps
	F _{OUT} < 100 MHz	—	_	75	mUI
t _{outjitter_ccj_io} <i>(6)</i>	Regular I/O cycle-to-cycle jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	650	ps
	F _{OUT} < 100 MHz	—	_	75	mUI
t _{PLL_PSERR}	Accuracy of PLL phase shift	—	_	±50	ps
t _{ARESET}	Minimum pulse width on areset signal.	10	_		ns
t _{CONFIGPLL}	Time required to reconfigure scan chains for PLLs	_	3.5 (7)		SCANCLK cycles
f _{scanclk}	scanclk frequency	—	—	100	MHz
t _{casc_outjitter_period_dedclk}	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} \ge 100 \text{ MHz}$)	_	_	425	ps
(8), (9)	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} < 100 \text{ MHz}$)	_		42.5	mUI

Table 1-25.	PLL Specifications	s for Cyclone IV Devices ^{(1),}	⁽²⁾ (Part 2 of 2)
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Notes to Table 1-25:

- (1) This table is applicable for general purpose PLLs and multipurpose PLLs.
- (2) You must connect $V_{\text{CCD_PLL}}$ to V_{CCINT} through the decoupling capacitor and ferrite bead.
- (3) This parameter is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.
- (4) The V_{C0} frequency reported by the Quartus II software in the PLL Summary section of the compilation report takes into consideration the V_{C0} post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VC0} specification.
- (5) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source that is less than 200 ps.
- (6) Peak-to-peak jitter with a probability level of 10⁻¹² (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL when an input jitter of 30 ps is applied.
- (7) With 100-MHz scanclk frequency.

(8) The cascaded PLLs specification is applicable only with the following conditions:

- $\blacksquare \quad Upstream \ PLL {----}0.59 \ MHz \leq Upstream \ PLL \ bandwidth < 1 \ MHz$
- Downstream PLL—Downstream PLL bandwidth > 2 MHz
- (9) PLL cascading is not supported for transceiver applications.

Table 1–29 lists the active configuration mode specifications for Cyclone IV devices.

Programming Mode	DCLK Range	Typical DCLK	Unit
Active Parallel (AP) ⁽¹⁾	20 to 40	33	MHz
Active Serial (AS)	20 to 40	33	MHz

Table 1–29. Active Configuration Mode Specifications for Cyclone IV Devices

Note to Table 1-29:

(1) AP configuration mode is only supported for Cyclone IV E devices.

Table 1-30 lists the JTAG timing parameters and values for Cyclone IV devices.

Table 1–30. JTAG Timing Parameters for Cyclone IV Devices (1)

Symbol	Parameter	Min	Max	Unit
t _{JCP}	TCK clock period	40	—	ns
t _{JCH}	TCK clock high time	19	_	ns
t _{JCL}	TCK clock low time	19	_	ns
t _{JPSU_TDI}	JTAG port setup time for TDI	1	_	ns
t _{JPSU_TMS}	JTAG port setup time for TMS	3	_	ns
t _{JPH}	JTAG port hold time	10	_	ns
t _{JPC0}	JTAG port clock to output ^{(2), (3)}	—	15	ns
t _{JPZX}	JTAG port high impedance to valid output ^{(2), (3)}	—	15	ns
t _{JPXZ}	JTAG port valid output to high impedance ^{(2), (3)}	—	15	ns
t _{JSSU}	Capture register setup time	5	_	ns
t _{JSH}	Capture register hold time	10	_	ns
t _{JSC0}	Update register clock to output	_	25	ns
t _{JSZX}	Update register high impedance to valid output	_	25	ns
t _{JSXZ}	Update register valid output to high impedance		25	ns

Notes to Table 1-30:

(1) For more information about JTAG waveforms, refer to "JTAG Waveform" in "Glossary" on page 1–37.

- (2) The specification is shown for 3.3-, 3.0-, and 2.5-V LVTTL/LVCMOS operation of JTAG pins. For 1.8-V LVTTL/LVCMOS and 1.5-V LVCMOS, the output time specification is 16 ns.
- (3) For EP4CGX22, EP4CGX30 (F324 and smaller package), EP4CGX110, and EP4CGX150 devices, the output time specification for 3.3-, 3.0-, and 2.5-V LVTTL/LVCMOS operation of JTAG pins is 16 ns. For 1.8-V LVTTL/LVCMOS and 1.5-V LVCMOS, the output time specification is 18 ns.

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/Os using the SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speeds. I/Os using general-purpose I/O standards such as 3.3-, 3.0-, 2.5-, 1.8-, or 1.5-LVTTL/LVCMOS are capable of a typical 200 MHz interfacing frequency with a 10 pF load.

Symbol	Modes		C6			C 7, I	7		C8, A	7		C8L, I	BL		C9L		Unit
Symbol	WOUCS	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIL
t _{LOCK} (3)				1	—	—	1	—	_	1		—	1			1	ms

Table 1–31. RSDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (2), (4)} (Part 2 of 2)

Notes to Table 1-31:

(1) Applicable for true RSDS and emulated RSDS_E_3R transmitter.

(2) Cyclone IV E devices—true RSDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Emulated RSDS transmitter is supported at the output pin of all I/O Banks. Cyclone IV GX devices—true RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is only supported at the

pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.
(3) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(4) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Gumbal	Madas		C6			C7, 17	,		C8, A7	7	(C8L, 18	SL		C9L		Unit
Symbol	Modes	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UNIT
	×10	5	—	85	5	—	85	5		85	5		85	5	—	72.5	MHz
	×8	5		85	5		85	5	-	85	5	_	85	5	—	72.5	MHz
f _{HSCLK} (input clock	×7	5	—	85	5	_	85	5	_	85	5	_	85	5	—	72.5	MHz
frequency)	×4	5		85	5		85	5	_	85	5	_	85	5	—	72.5	MHz
,	×2	5	_	85	5	_	85	5		85	5		85	5	_	72.5	MHz
	×1	5	_	170	5	_	170	5	_	170	5	_	170	5	—	145	MHz
	×10	100		170	100		170	100	_	170	100	_	170	100	—	145	Mbps
	×8	80	_	170	80		170	80	_	170	80	_	170	80	—	145	Mbps
Device operation in	×7	70	_	170	70		170	70	_	170	70	_	170	70	—	145	Mbps
Mbps	×4	40	—	170	40	_	170	40	_	170	40	_	170	40	—	145	Mbps
	×2	20	_	170	20		170	20	_	170	20	_	170	20	—	145	Mbps
	×1	10	_	170	10	_	170	10	_	170	10	_	170	10	—	145	Mbps
t _{DUTY}	—	45	_	55	45	-	55	45	_	55	45	_	55	45	—	55	%
TCCS	—	—	_	200	_		200	_	_	200	_	_	200	_	—	200	ps
Output jitter (peak to peak)	_	_	_	500	_	_	500	_	_	550	_	_	600	_		700	ps
	20-80%,																
t _{RISE}	C _{LOAD} = 5 pF	-	500		_	500		_	500		_	500		_	500	—	ps
t _{FALL}	20 - 80%, C _{LOAD} =	_	500	_	_	500	_	_	500	_	_	500	_	_	500		ps
	5 pF																

Table 1–32. Emulated RSDS_E_1R Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)} (Part 1 of 2)

Symbol	Modes		C6			C7, 17			C8, A7	7		C8L, 18	L		C9L		Unit
əyiinui	WIUUES	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
t _{LOCK} (2)	_	—		1		—	1	_		1			1		—	1	ms

Table 1–32. Emulated RSDS_E	1R Transmitter Timing	Specifications for C	vclone IV Devices ^{(1), (3)}	(Part 2 of 2)
		• • • • • • • • • • • • • • • • •		(

Notes to Table 1-32:

(1) Emulated RSDS_E_1R transmitter is supported at the output pin of all I/O Banks of Cyclone IV E devices and I/O Banks 3, 4, 5, 6, 7, 8, and 9 of Cyclone IV GX devices.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Gumbal	Modes		C6			C7, 17	7		C8, A	7		C8L, I	8L		C9L		Unit
Symbol	woues	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIL
	×10	5	—	200	5	—	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
	×8	5	_	200	5	—	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
f _{HSCLK} (input clock	×7	5	_	200	5	_	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
frequency)	×4	5	_	200	5	—	155.5	5	—	155.5	5		155.5	5		132.5	MHz
,	×2	5	_	200	5	_	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
	×1	5	_	400	5	_	311	5	—	311	5	_	311	5	_	265	MHz
	×10	100	_	400	100	_	311	100	—	311	100		311	100		265	Mbps
	×8	80	_	400	80	_	311	80	—	311	80	_	311	80	_	265	Mbps
Device operation in	×7	70	_	400	70	—	311	70	—	311	70	_	311	70	—	265	Mbps
Mbps	×4	40	—	400	40	—	311	40	—	311	40	_	311	40	—	265	Mbps
	×2	20		400	20		311	20	_	311	20		311	20	_	265	Mbps
	×1	10	_	400	10	—	311	10		311	10	_	311	10		265	Mbps
t _{DUTY}	—	45	_	55	45	_	55	45	—	55	45		55	45		55	%
TCCS	—	_	_	200	_	_	200	_	—	200	_	_	200	_	_	200	ps
Output jitter (peak to peak)	—	_	_	500	_	_	500	_		550	_	_	600		_	700	ps
t _{RISE}	20 - 80%, C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500	_	_	500	_	ps
t _{FALL}	20 - 80%, C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500	_	_	500	_	ps
t _{LOCK} (3)				1			1			1			1			1	ms

Table 1–33. Mini-LVDS Transmitter Timing Specifications for Cyclone IV Devices (1), (2), (4)

Notes to Table 1-33:

(1) Applicable for true and emulated mini-LVDS transmitter.

(2) Cyclone IV E—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Emulated mini-LVDS transmitter is supported at the output pin of all I/O banks.
Cyclone IV GY—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5.

Cyclone IV GX—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.

(3) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(4) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Gumbal	Madaa	C	6	C 7	, 17	C 8,	, A7	C8L	, 18L	C	9L	11
Symbol	Modes	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
	×10	5	420	5	370	5	320	5	320	5	250	MHz
	×8	5	420	5	370	5	320	5	320	5	250	MHz
f _{HSCLK} (input	×7	5	420	5	370	5	320	5	320	5	250	MHz
clock frequency)	×4	5	420	5	370	5	320	5	320	5	250	MHz
	×2	5	420	5	370	5	320	5	320	5	250	MHz
	×1	5	420	5	402.5	5	402.5	5	362	5	265	MHz
	×10	100	840	100	740	100	640	100	640	100	500	Mbps
	×8	80	840	80	740	80	640	80	640	80	500	Mbps
	×7	70	840	70	740	70	640	70	640	70	500	Mbps
HSIODR	×4	40	840	40	740	40	640	40	640	40	500	Mbps
	×2	20	840	20	740	20	640	20	640	20	500	Mbps
	×1	10	420	10	402.5	10	402.5	10	362	10	265	Mbps
t _{DUTY}	—	45	55	45	55	45	55	45	55	45	55	%
TCCS	—	_	200	_	200	—	200		200	—	200	ps
Output jitter (peak to peak)	_	_	500	_	500	_	550		600	_	700	ps
t _{LOCK} (2)	—	—	1	—	1		1	—	1	—	1	ms

Table 1–34. True LVDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)}

Notes to Table 1-34:

(1) Cyclone IV E—true LVDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Cyclone IV GX—true LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–35. Emulated LVDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)} (Part 1 of 2)

Symbol	Modes	C6		C7, I7		C8, A7		C8L, 18L		C9L		Ilait
Symbol		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
	×10	5	320	5	320	5	275	5	275	5	250	MHz
	×8	5	320	5	320	5	275	5	275	5	250	MHz
f _{HSCLK} (input clock	×7	5	320	5	320	5	275	5	275	5	250	MHz
frequency)	×4	5	320	5	320	5	275	5	275	5	250	MHz
1 37	×2	5	320	5	320	5	275	5	275	5	250	MHz
	×1	5	402.5	5	402.5	5	402.5	5	362	5	265	MHz
	×10	100	640	100	640	100	550	100	550	100	500	Mbps
	×8	80	640	80	640	80	550	80	550	80	500	Mbps
HSIODR	×7	70	640	70	640	70	550	70	550	70	500	Mbps
	×4	40	640	40	640	40	550	40	550	40	500	Mbps
	×2	20	640	20	640	20	550	20	550	20	500	Mbps
	×1	10	402.5	10	402.5	10	402.5	10	362	10	265	Mbps

Symbol	Modes	C6		C7, I7		C8, A7		C8L, I8L		C9L		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	UIII
t _{DUTY}	—	45	55	45	55	45	55	45	55	45	55	%
TCCS	—	_	200	—	200	_	200	_	200	—	200	ps
Output jitter (peak to peak)	_		500	_	500	_	550	_	600	_	700	ps
t _{LOCK} (2)	_		1	_	1		1	_	1	_	1	ms

Table 1–35. Emulated LVDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)} (Part 2 of 2)

Notes to Table 1-35:

(1) Cyclone IV E—emulated LVDS transmitter is supported at the output pin of all I/O Banks.

Cyclone IV GX—emulated LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Gumbal	Modes	C6		C7, 17		C8, A7		C8L, 18L		C9L		11
Symbol		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
f _{HSCLK} (input clock frequency)	×10	10	437.5	10	370	10	320	10	320	10	250	MHz
	×8	10	437.5	10	370	10	320	10	320	10	250	MHz
	×7	10	437.5	10	370	10	320	10	320	10	250	MHz
	×4	10	437.5	10	370	10	320	10	320	10	250	MHz
, ,,	×2	10	437.5	10	370	10	320	10	320	10	250	MHz
	×1	10	437.5	10	402.5	10	402.5	10	362	10	265	MHz
	×10	100	875	100	740	100	640	100	640	100	500	Mbps
	×8	80	875	80	740	80	640	80	640	80	500	Mbps
HSIODR	×7	70	875	70	740	70	640	70	640	70	500	Mbps
HOIDDN	×4	40	875	40	740	40	640	40	640	40	500	Mbps
	×2	20	875	20	740	20	640	20	640	20	500	Mbps
	×1	10	437.5	10	402.5	10	402.5	10	362	10	265	Mbps
SW	—	_	400	_	400	_	400	_	550	—	640	ps
Input jitter tolerance	_	_	500	_	500	_	550	_	600	_	700	ps
t _{LOCK} (2)	—	—	1	_	1	_	1	—	1	—	1	ms

Table 1–36. LVDS Receiver Timing Specifications for Cyclone IV Devices (1), (3)

Notes to Table 1-36:

(1) Cyclone IV E—LVDS receiver is supported at all I/O Banks.

Cyclone IV GX—LVDS receiver is supported at I/O Banks 3, 4, 5, 6, 7, 8, and 9.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

External Memory Interface Specifications

The external memory interfaces for Cyclone IV devices are auto-calibrating and easy to implement.

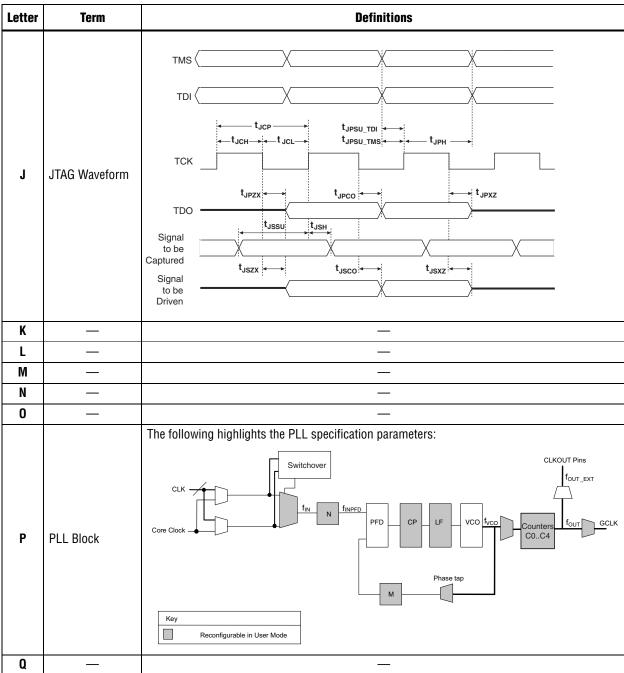


Table 1-46. Glossary (Part 2 of 5)

Letter	Term	Definitions										
	t _C	High-speed receiver and transmitter input and output clock period.										
	Channel-to- channel-skew (TCCS)	gh-speed I/O block: The timing difference between the fastest and slowest output edges, cluding t _{CO} variation and clock skew. The clock is included in the TCCS measurement.										
	t _{cin}	Delay from the clock pad to the I/O input register.										
	t _{co}	Delay from the clock pad to the I/O output.										
	t _{cout}	Delay from the clock pad to the I/O output register.										
	t _{DUTY}	High-speed I/O block: Duty cycle on high-speed transmitter output clock.										
	t _{FALL}	Signal high-to-low transition time (80–20%).										
	t _H	Input register hold time.										
	Timing Unit Interval (TUI)	High-speed I/O block: The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = $1/(\text{Receiver Input Clock Frequency Multiplication Factor}) = t_C/w)$.										
	t _{INJITTER}	Period jitter on the PLL clock input.										
	t _{outjitter_dedclk}	Period jitter on the dedicated clock output driven by a PLL.										
	t _{outjitter_i0}	Period jitter on the general purpose I/O driven by a PLL.										
	t _{pllcin}	Delay from the PLL inclk pad to the I/O input register.										
т	t _{plicout}	Delay from the PLL inclk pad to the I/O output register.										
	Transmitter Output Waveform	Transmitter output waveforms for the LVDS, mini-LVDS, PPDS and RSDS Differential I/O Standards: Single-Ended Waveform V_{OD} $V_{$										
	t _{RISE}	Signal low-to-high transition time (20–80%).										
	t _{SU}	Input register setup time.										
U	— —	_										

Table 1–46. Glossary (Part 4 of 5)